

**AMENDMENTS TO THE CLAIMS:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

**LISTING OF CLAIMS:**

1 to 5. (Canceled).

6. (Previously Presented) A tunable interferometer for measuring an optical surface, comprising:

at least one light source;

a reference surface, light from the at least one light source impinging the reference surface, the reference surface reflecting a first interference beam, wherein the reference surface is stationary when at least one light source impinges the reference surface;

a test object, light from the at least one light source impinging the test object, the test object reflecting a second interference beam;

at least one beam splitter, the first interference beam and the second interference beam striking the at least one beam splitter; and

a polarizer polarizing the first interference beam and the second interference beam so that the first interference beam and the second interference beam each have a different polarization state relative to one another; and

an analyzer positioned at an output of the interferometer, the analyzer having a variable polarization state, the analyzer tuning the interferometer as a function of the polarized first interference beam and the second interference beam, wherein depending on the polarization state of the analyzer, an additional phase is introduced into at least one of the first and second interference beams of different polarizations so that an interference fringe pattern is displaced by a distance.

7. (Previously Presented) The interferometer according to claim 6, wherein the interferometer is a two-beam interferometer, wherein the light is a linearly polarized light, and wherein the polarizer includes a first  $\lambda/4$  retardation plate allocated to one of the reference surface and the test object, and a second  $\lambda/4$  retardation plate positioned before the analyzer.

8. (Previously Presented) The interferometer according to claim 6, wherein the analyzer includes a rotatable linear analyzer.

9. (Previously Presented) The interferometer according to claim 6, wherein the analyzer includes an electrically tunable liquid-crystal element with a linear polarizer.

10. (Previously Presented) The interferometer according to claim 6, wherein the analyzer is arranged physically separate from the interferometer.

11. (Previously Presented) The interferometer of claim 6, wherein the test object is stationary when the at least one light source impinges the test object.

12. (Previously Presented) A tunable interferometer for measuring an optical surface, comprising:

at least one light source;

a reference surface, light from the at least one light source impinging the reference surface, the reference surface reflecting a first interference beam;

a test object, light from the at least one light source impinging the test object, the test object reflecting a second interference beam; at least one beam splitter, the first interference beam and the second interference beam striking the at least one beam splitter; and

a polarizer polarizing the first interference beam and the second interference beam so that the first interference beam and the second interference beam each have a different polarization state relative to one another; and

an analyzer positioned at an output of the interferometer, the analyzer having a variable polarization state, the analyzer tuning the interferometer as a function of the polarized first interference beam and the second interference beam, wherein depending on the polarization state of the analyzer, an additional phase is introduced into at least one of the first and second interference beams of different polarizations so that an interference fringe pattern is displaced by a distance.

13. (Previously Presented) The interferometer according to claim 12, wherein the interferometer is a two-beam interferometer, wherein the light is a linearly polarized light, and wherein the polarizer includes a first  $\lambda/4$  retardation plate allocated to one of the reference surface and the test object, and a second  $\lambda/4$  retardation plate positioned before the analyzer.

14. (Previously Presented) The interferometer according to claim 12, wherein the analyzer includes a rotatable linear analyzer.

15. (Previously Presented) The interferometer according to claim 12, wherein the analyzer includes an electrically tunable liquid-crystal element with a linear polarizer.

16. (Previously Presented) The interferometer according to claim 12, wherein the analyzer is arranged physically separate from the interferometer.